

Ifw



In the United States Patent and Trademark Office

Serial Number: 10/772,053
Appn. Filed: 02/03/04
Applicant: Guobiao Zhang
Appn. Title: Three-Dimensional-Memory-Based Self-Test
Integrated Circuits and Methods
Examiner/GAU: Pham, Long/2814

Mailed: July 28, 2005

Commissioner of Patents and Trademarks
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Office Action mailed July 12, 2005, Applicant elects to have claims 1-12 and 18-20 examined. If there are any questions, Applicant can be contacted by email at gzhang@3d-rom.net.

Very respectfully,

Guobiao Zhang
Applicant Pro Se

P.O. Box 6182
Stateline, NV 89449-6182
(650) 575-2014